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| FORM PTO-1449 | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | ATTY. DOCKET NO. IMEC215.001C1 | APPLICATION NO. 10/630,439 |
| INFORMATION DISCLOSURE STATEMENT BY APPLICANT | | APPLICANT Meuris, et al. | |
| (USE SEVERAL SHEETS IF NECESSARY) | | FILING DATE July 29, 2003 | GROUP Unknown |

| U.S. PATENT DOCUMENTS | | | | | | |
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| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS |
| JW | 1. | 6,051,027 | 4/2000 | Kapur et al. | | |
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| EXAMINER | DATE CONSIDERED |
| JW | 3/9/06 |
| *EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT. | |